



18. TEST PHOTOGRAPHS

See following Attached Pages for setup photographs.

FCC ID: A3LSMG960U	 PCTEST ENGINEERING LABORATORY, INC.	HAC (RF EMISSIONS) TEST REPORT		Approved by: Quality Manager
Filename: 1M1711010281-13-R1.A3L	Test Dates: 11/06/2017 - 12/11/2017	DUT Type: Portable Handset	Page 102 of 104	

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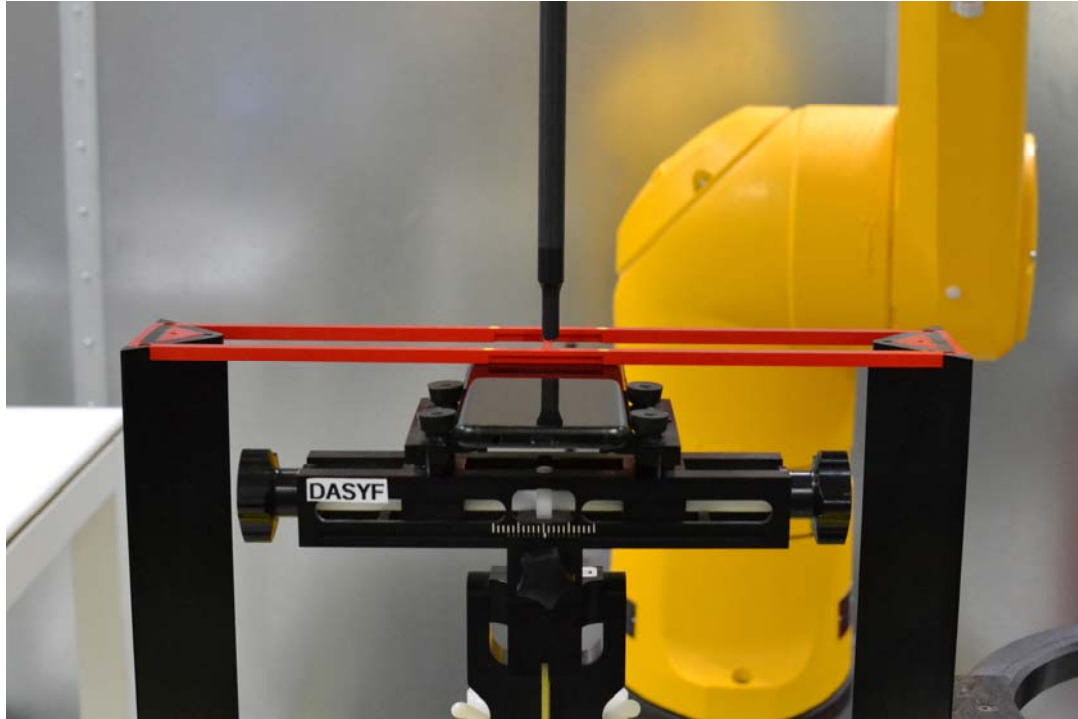


Figure 18-1
Ear Reference Point HAC Phantom Alignment

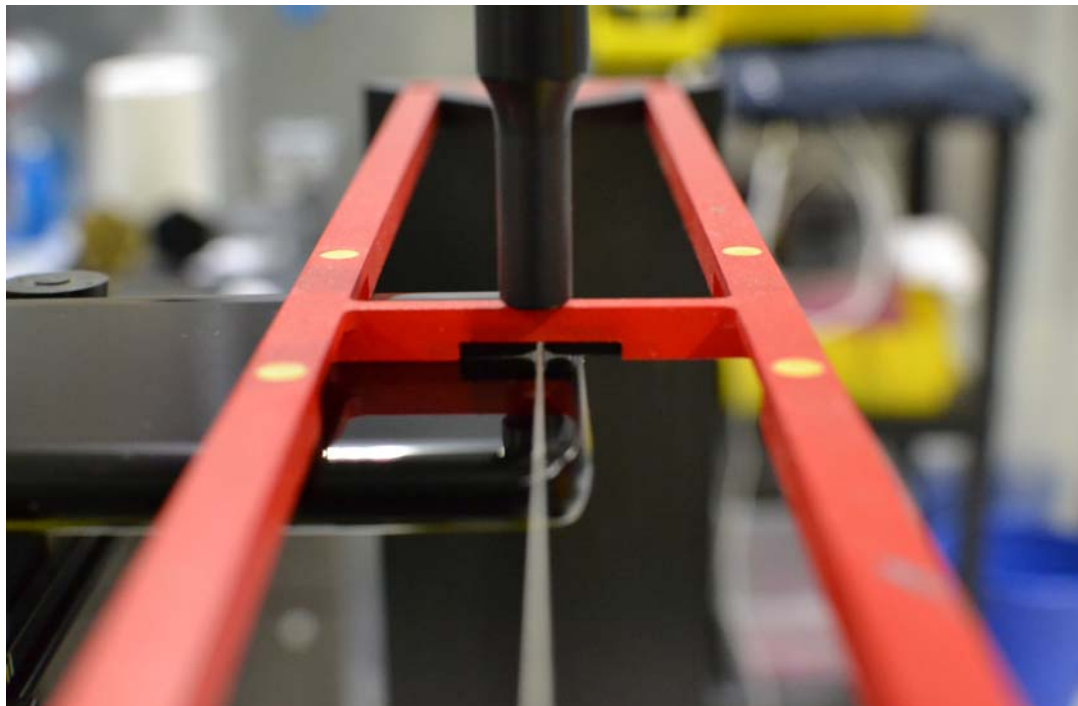




Figure 18-2
HAC Phantom Plane Alignment

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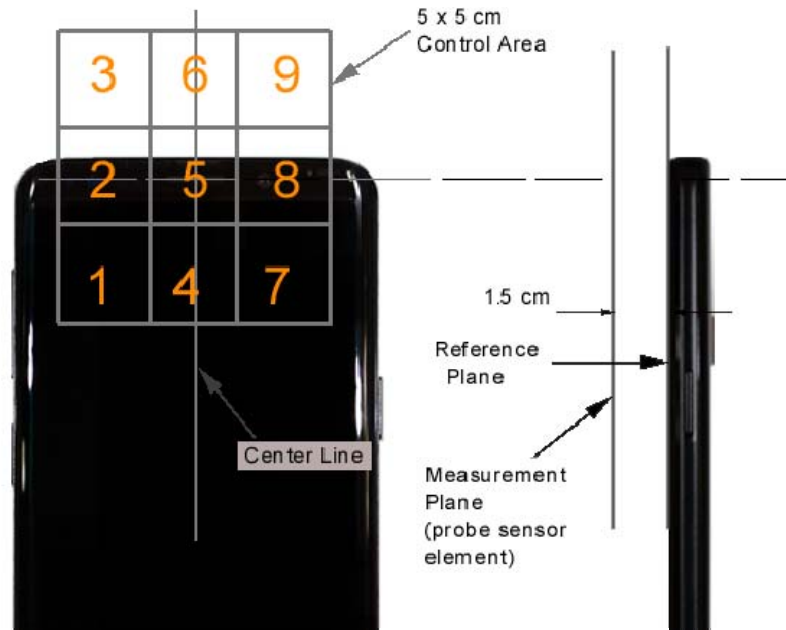




Figure 18-3 5x5 Scan grid above WD



Figure 18-4 E-Field WD Scan overlay

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